

PATENT



ATTORNEY DOCKET NO.: D5116-00002

2812
1/4/01
Jen

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE **RECEIVED**

In re Application of: Saxena et al.

Art Unit: 2812

JUN 12 2001

Serial No.: 09/675,427

Technology Center 2100

Filed: September 29, 2000

For: Efficient Method for Modeling and Simulation of the Impact of Local and Global Variation on Integrated Circuits

I CERTIFY THAT THIS CORRESPONDENCE IS BEING DEPOSITED WITH THE U.S. POSTAL SERVICE AS FIRST CLASS MAIL IN AN ENVELOPE ADDRESSED TO THE ASSISTANT COMMISSIONER FOR PATENTS, WASHINGTON, D.C. 20231

ON May 22, 2001
Mary La Grange

RECEIVED
JUN 30 2001
TECHNOLOGY CENTER 2800

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

INFORMATION DISCLOSURE STATEMENT TRANSMITTAL LETTER

Enclosed herewith is an Information Disclosure Statement pursuant to 37 CFR.

§ 1.56 in connection with the above-identified application, which statement is being filed:

- ☐ Together with the present application.
- ☒ Before the first Office Action on the merits or three (3) months from the filing date of this application, whichever occurs last. [37 CFR § 1.97(b)]

- ☐ After the first Office Action on the merits, but before a Final Office Action under §1.113 or Notice of Allowance under §1.311, whichever occurs first. [37 CFR § 1.97(c)]
- ☐ After a Final Office Action under §1.113 or Notice of Allowance under §1.311, but prior to or with payment of the Issue Fee. [37 CFR § 1.97(d)]

Consistent with Applicant's obligations pursuant to 37 CFR §§1.97 and 1.98, the following requirements have been met:

- ☒ No separate requirements are needed.
- ☒ No additional fee is required.

☐ **Fee Under 37 CFR § 1.97(c) or 1.97(d)**

The fee of \$180.00 for submission of an IDS under § 1.97(c) as set forth in § 1.17(p) accompanies this statement.

☐ **Certification Under 37 CFR § 1.97(e)**

The undersigned certifies:

- ☐ 1 that each item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement; or
- ☐ 2 that no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the statement after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in §1.56(c) more than three months prior to the filing of the information disclosure statement.

Provision of Copies of References

- ☒ A copy of each of the references listed on the attached Form PTO-1449 is enclosed herewith and forms a part hereof.
- ☐ A translation of Reference___ is enclosed herewith and forms a part hereof.
- ☐ A copy of the European Search Report from a corresponding or related EPO application is enclosed herewith.
- ☐ A copy of the International Search Report from a corresponding or related PCT application is enclosed herewith.

Identification of Prior Application(s) In Which Listed Information Was Already Cited And For Which No Copies Are Submitted Or Need Be Submitted

- ☐ This application relies, under 35 U.S.C. § 120, on the earlier filing date of prior U.S. Application No(s). _____, filed _____. The following references were submitted to, and/or cited by, the Office in the prior application(s) and therefore are not required to be provided in this application:
- ☒ The Commissioner is hereby authorized to charge any fees associated with this communication or credit any overpayment to Deposit Account No. 04-1679. A duplicate copy of this transmittal is attached.

Date: May 22, 2001

DUANE, MORRIS & HECKSCHER LLP
One Liberty Place
Philadelphia, PA 19103-7396
215-979-1250 tel
215-979-1020 fax

Respectfully submitted,


STEVEN E. KOFFS
Registration No. 37,163

Form PTO-1449 U.S. Department of Commerce Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION (Use several sheets if necessary)	Docket No. D5116-00002	Serial No. 09/675,427
	Applicant Saxena et al.	
	Filing Date September 29, 2000	Group Art Unit 2812



U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,767,542	6/16/98	Nakamura	57	296	
	AB	5,773,315	6/30/98	Jarvis	438	14	
	AC	6,184,048	2/6/01	Ramon	438	14	

TECHNOLOGY CENTER 2800

JUN 30 2001

RECEIVED

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
								X
								X

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)

A	International Search Report dated 09 APR 2001
B	Khare et al., "Extraction of Defect Characteristics for Yield Estimation Using The Double Bridge Test Structure", IEEE, May 1991, pages 428-432
C	Yun et al., "Evaluating the Manufacturability of GaAs/AlGaAs Multiple Quantum Well Avalanche Photodiodes Using Neural Networks, IEEE, Oct 1997, pages 105-112
D	Hansen et al., "Effectiveness of Yield-Estimation and Reliability-Prediction Based on Wafer Test-Chip Measurements", IEEE, Jan 1997, pages 142-148

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.	

RECEIVED
JUN 12 2001
Technology Center 2100